## N-Channel Enhancement Mode Power MOSFET

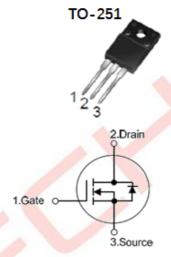
Drain-Source Voltage: 650V Continuous Drain Current: 2A

#### DESCRIPTION

The ATM2N65TD is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

#### **FEATURES**

- $R_{DS(ON)} < 5.0\Omega$  @  $V_{GS} = 10V$
- Ultra Low gate charge (typical 45nC)
- Low reverse transfer capacitance (C<sub>RSS</sub> = typical 9 pF)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability, high ruggedness



### ABSOLUTE MAXIMUM RATINGS (Tc = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{DSS}$	650	V
Gate-Source Voltage		$V_{GSS}$	±30	V
Avalanche Current (Note 2)		I <sub>AR</sub>	2.0	Α
Drain Current	Continuous	I <sub>D</sub>	2.0	Α
	Pulsed (Note 2)	$I_{DM}$	8.0	Α
Avalanche Energy	Single Pulsed (Note 3)	E <sub>AS</sub>	140	mJ
	Repetitive (Note 2)	$E_{AR}$	4.5	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation	TO-251	P□	28	W
Junction Temperature		TJ	+150	°C
Operating Temperature		$T_{OPR}$	-55 ~ <b>+</b> 150	°C
Storage Temperature		$T_{STG}$	-55 ~ <b>+</b> 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by T<sub>J</sub>.
- 3. L=64mH,  $I_{AS}$ =2.0A,  $V_{DD}$ =50V,  $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}$ C
- 4. I<sub>SD</sub>≤2.4A, di/dt≤200A/µs, V<sub>DD</sub>≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C



Dated:12/2017 Rev: 2.0

# ATM2N65TD

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> =25°C, unless otherwise specified)

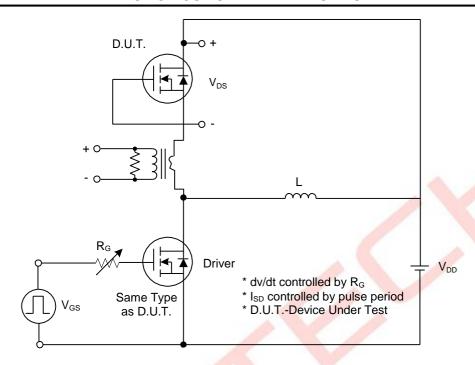
SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT				
OFF CHARACTERISTICS									
BV <sub>DSS</sub>	$V_{GS} = 0V, I_{D} = 250\mu A$	650			V				
I <sub>DSS</sub>	$V_{DS} = 650 V, V_{GS} = 0 V$			10	μA				
	$V_{GS} = 30V$ , $V_{DS} = 0V$			100	nA				
IGSS	$V_{GS} = -30V$ , $V_{DS} = 0V$			-100	nA				
△BV <sub>DSS</sub> /△T <sub>J</sub>	I <sub>D</sub> =250µA, Referenced to 25°C		0.4		V/°C				
ON CHARACTERISTICS									
$V_{GS(TH)}$	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	2.0		4.0	V				
R <sub>DS(ON)</sub>	$V_{GS} = 10V, I_{D} = 1A$	4	3.9	5.0	Ω				
DYNAMIC CHARACTERISTICS									
C <sub>ISS</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f =1MHz		320	370	pF				
Coss			40	50	pF				
C <sub>RSS</sub>			9	12	pF				
		1							
t <sub>D (ON)</sub>	V <sub>DD</sub> =325V, I <sub>D</sub> =2.4A, R <sub>G</sub> =25Ω (Note 1, 2)		35	50	ns				
$t_R$			40	60	ns				
t <sub>D(OFF)</sub>			130	160	ns				
t <sub>F</sub>			40	60	ns				
Q <sub>G</sub>	V <sub>DS</sub> =520V, V <sub>GS</sub> =10V, I <sub>D</sub> =2.4A (Note 1, 2)		45	55	nC				
$Q_{GS}$			4		nC				
$Q_{GD}$			8.4		nC				
Gate-Drain Charge Q <sub>GD</sub> N N N N N N N N N N N N N N N N N N N									
V <sub>SD</sub>	$V_{GS} = 0 \text{ V}, I_{SD} = 2.0 \text{ A}$			1.4	V				
I <sub>SD</sub>				2.0	Α				
I <sub>SM</sub>				8.0	Α				
t <sub>rr</sub>	$V_{GS} = 0 \text{ V}, I_{SD} = 2.4A,$		180		ns				
Q <sub>RR</sub>	di/dt = 100 A/µs (Note1)		0.72		μC				
	BVDSS IDSS IDSS IGSS IGSS  VGS(TH) RDS(ON)  CISS COSS CRSS  tD (ON)  tR  tD(OFF)  tF  QG QGS QGD ISD ISM trr	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{ c c c c c c c } \hline BV_{DSS} & V_{GS} = 0V, \ I_D = 250 \mu A & 650 \\ \hline I_{DSS} & V_{DS} = 650 V, \ V_{GS} = 0 V & 10 \\ \hline I_{GSS} & V_{GS} = 30 V, \ V_{DS} = 0 V & 100 \\ \hline V_{GS} = -30 V, \ V_{DS} = 0 V & -100 \\ \hline \vdots & \triangle BV_{DSS}/\triangle T_J & I_D = 250 \mu A, \ Referenced to 25^{\circ}C & 0.4 \\ \hline \hline V_{GS(TH)} & V_{DS} = V_{GS}, \ I_D = 250 \mu A & 2.0 & 4.0 \\ \hline R_{DS(ON)} & V_{GS} = 10 V, \ I_D = 1A & 3.9 & 5.0 \\ \hline \hline C_{ISS} & V_{DS} = 25 V, \ V_{GS} = 0 V, \\ \hline C_{COSS} & f = 1 MHz & 9 & 12 \\ \hline \hline t_D (ON) & 35 & 50 \\ \hline t_R & V_{DD} = 325 V, \ I_D = 2.4 A, & 40 & 60 \\ \hline t_F & 40 & 60 \\ \hline Q_G & V_{DS} = 520 V, \ V_{GS} = 10 V, \\ \hline Q_{GD} & V_{DS} = 520 V, \ V_{GS} = 10 V, \\ \hline C_{S} & V_{SD} & V_{GS} = 0 V, \ I_{SD} = 2.0 \ A & 1.4 \\ \hline I_{SD} & 2.0 \\ \hline I_{SM} & 8.0 \\ \hline t_{rr} & V_{GS} = 0 \ V, \ I_{SD} = 2.4 A, & 180 \\ \hline \end{array}$				

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

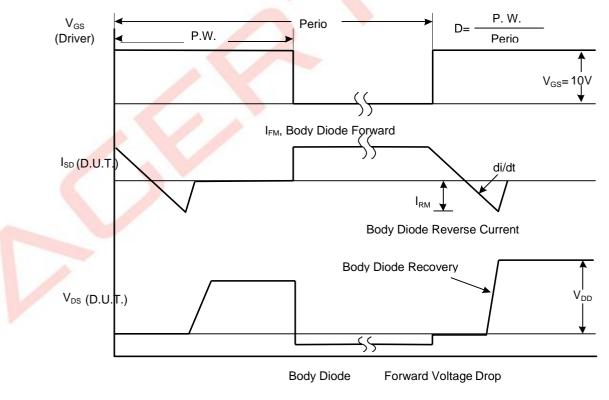


<sup>2.</sup> Essentially independent of operating temperature

#### **TEST CIRCUITS AND WAVEFORMS**



#### Peak Diode Recovery dv/dt Test Circuit

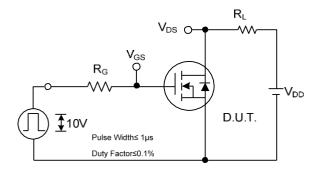


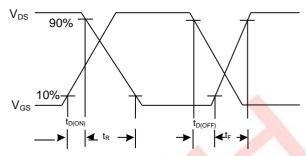
Peak Diode Recovery dv/dt Waveforms



AGERTECH MICROELECTRONICS

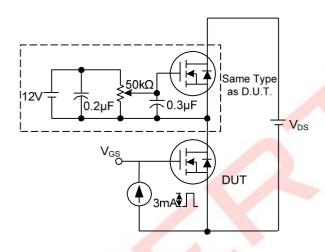
### **TEST CIRCUITS AND WAVEFORMS (Cont.)**

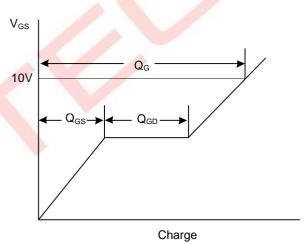




**Switching Test Circuit** 

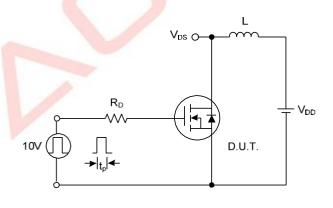
**Switching Waveforms** 

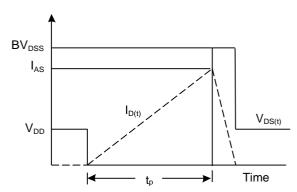




**Gate Charge Test Circuit** 

**Gate Charge Waveform** 





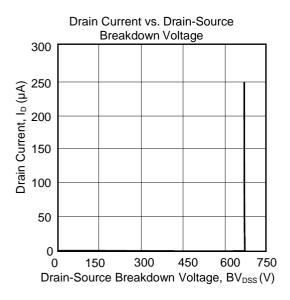
**Unclamped Inductive Switching Test Circuit** 

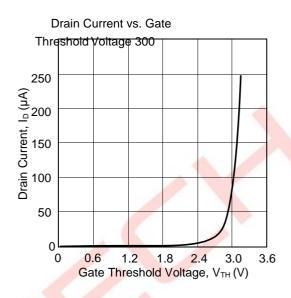
**Unclamped Inductive Switching Waveforms** 

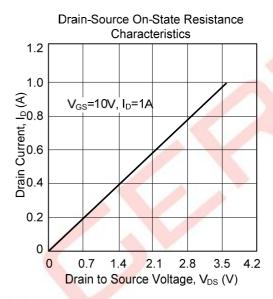


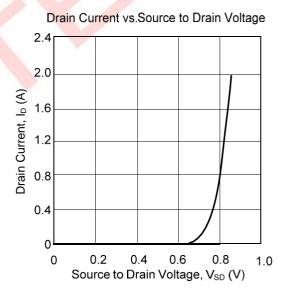
## ATM2N65TD

#### **TYPICAL CHARACTERISTICS CURVES**











## Package Outline

TO-251

